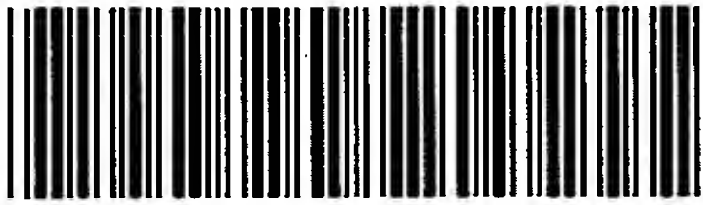


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/707,518	CHEN ET AL.	
	Examiner	Art Unit	
	Matthew G. Kayrish	2653	

SEARCHED			
Class	Subclass	Date	Examiner
720	610	11/8/2005	MK
720	610	11/15/2005	MK

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East (USPG-PUB, USPAT, USOCR) (See Attached Search Notes)	11/8/2005	MK
East (USPG-PUB, USPAT, USOCR) (See Attached Search Notes)	11/9/2005	MK
East (USPG-PUB, USPAT, USOCR) (See Attached Search Notes)	11/10/2005	MK
East (USPG-PUB, USPAT, USOCR) (See Attached Search Notes)	11/14/2005	MK
East (USPG-PUB, USPAT, USOCR) (See Attached Search Notes)	11/15/2005	MK